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LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Nghi NGUYEN, et al.			
				FILING DATE May 12, 2006		GROUP 1615	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	5,690,924	11-25-97	KEIL ET AL.			
	AB	4,845,204	07-04-89	LANG ET AL.			
	AC	5,494,659	02-27-96	SALKA ET AL.			
	AD	6,369,117	04-09-02	DUBIEF ET AL.			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AE	09-067234	03-11-97	JAPAN w/Attached English Abstract (Corresponds to U.S. Patent 5,690,924)		X	
	AF	08-020516	01-23-96	JAPAN w/Attached English Abstract		X	
	AG	2002-518423	06-25-02	JAPAN (Corresponds to WO 99/66888)		X	
	AH	WO 99/66888	12-29-99	WIPO			
	AI	08-217645	08-27-96	JAPAN w/Attached English Abstract		X	
	AJ	06-100419	04-12-94	JAPAN w/Attached English Abstract		X	
	AK	2000-290143	10-17-00	JAPAN w/Attached English Abstract			
	AL	2002-029945	01-02-29	JAPAN w/Attached English Abstract			
	AM	62-501711	07-09-87	JAPAN (Corresponds to U.S. Patent No. 4,845,204)			
	AN	02-134312	05-23-90	JAPAN w/Attached English Abstract			
	AO	2000-319145	11-21-00	JAPAN w/Attached English Abstract (Corresponds to WO 00/67709)			
	AP	WO 00/67709	11-16-00	WIPO			
	AQ	WO 02/078655	10-10-02	WIPO			
	AR	2000-273029	10-03-00	JAPAN w/Attached English Abstract			
	AS	09-501684	02-18-97	JAPAN (Corresponds to U.S. Patent No. 5,494,659)			
	AT	06-505973	07-07-94	JAPAN (Corresponds to CA 2,107,120)			
	AU	2,107,120	09-28-92	Canada			
	AV	WO 01/68040	09-20-01	WIPO			
	AW	03-063214	03-19-91	JAPAN w/Attached English Abstract (Corresponds to EP 0 403 282)			
	AX	0 403 282	12-19-90	EUROPE			
	AY	06-40853	02-15-94	JAPAN w/Attached English Abstract			
	AZ	2002-249413	09-06-02	JAPAN w/Attached English Abstract			
	AAA	2000-508373	07-04-00	JAPAN (Corresponds to WO 98/31751 and U.S. Patent No. 6,369,117)			
	AAB	WO 98/31751	07-23-98	WIPO			
	AAC	2001-19626	01-23-01	JAPAN w/Attached English Abstract			
Examiner					Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							